

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 15: Resistance to soldering temperature for through-hole mounted devices**

**Dispositifs à semiconducteurs – Méthodes d'essai mécaniques et climatiques –
Partie 15: Résistance à la température de soudage pour dispositifs par trous
traversants**



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**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 15: Resistance to soldering temperature
for through-hole mounted devices**

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International Standard IEC 60749-15 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2003 and constitutes a technical revision. The significant changes with respect from the previous edition include:

- editorial change in the scope,
- addition of lead-free solder chemical composition specification.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/2067/FDIS	47/2078/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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